

L Number	Hits	Search Text	DB	Time stamp
1	2	4693780.pn.	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 08:36
9	86	(wafer or substrate) same ( BARC or "antireflective") same (edge or circumference or peripheral)	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 08:45
10	555	(wafer) and ( BARC or "antireflective") and (resist or photoresist) and (edge or circumference or peripheral)	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 09:40
11	2334	(wafer) and ( BARC or "antireflective" or ARC) and (resist or photoresist) and (edge or peripheral)	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 09:41
12	50	(wafer) same ( BARC or "antireflective" or ARC) same (resist or photoresist) same (edge or peripheral)	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 11:13
14	305	((wafer) same ( BARC or "antireflective" or ARC) same (resist or photoresist) ) and (edge or peripheral)	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 09:47
13	772	(wafer) same ( BARC or "antireflective" or ARC) same (resist or photoresist)	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 10:28
15	696	(substrate) same ( BARC or "antireflective" ) same (resist or photoresist)	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 10:29
16	1		USPAT	2004/09/27 11:07
17	1		USPAT	2004/09/27 11:08
22	245	(wafer or substrate) same ( BARC or polyimide) same (resist or photoresist) same (edge or circumference)	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 11:13
23	3187	((430/311) or (430/322)).CCLS.	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 11:14
24	109	((430/311) or (430/322)).CCLS.) and ((wafer) and ( BARC or "antireflective" or ARC) and (resist or photoresist) and (edge or peripheral))	USPAT; EPO; JPO; DERWENT; IBM TDB	2004/09/27 11:14